

# PATENT ABSTRACTS OF JAPAN

(11)Publication number : 11-347614

(43)Date of publication of application : 21.12.1999

(51)Int.Cl.

B21B 37/18

B21B 37/18

B21C 51/00

(21)Application number : 10-158218

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(22)Date of filing : 05.06.1998

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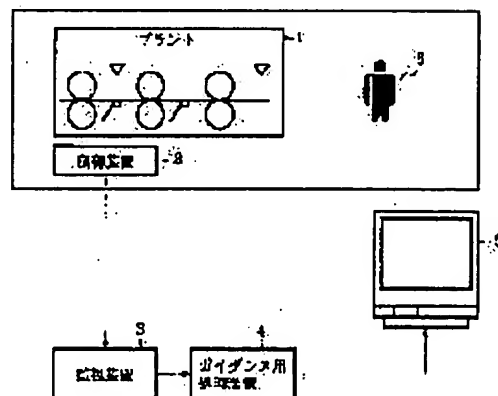
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## (54) METHOD AND DEVICE FOR ABNORMALITY DIAGNOSIS

### (57)Abstract:

**PROBLEM TO BE SOLVED:** To diagnose an abnormal plate thickness under rolling by calculating a deviation between the plate thickness of a rolling material to be rolled and a target plate thickness and recognizing the abnormal plate thickness when the deviation exceeds a reference value.

**SOLUTION:** A control device (measuring means) 2 measures the plate thickness of a rolling material. A monitor device (calculating means, recognizing means) 3 calculates a deviation between an actual plate thickness and a target plate thickness and the deviation is compared to a discrimination reference value of a plate thickness abnormality. In the case that the deviation exceeds the discrimination reference value, it is recognized as the plate thickness abnormal. It is desirable to detect a local min value and local max value of the plate thickness. A cause of the abnormality is desirably assumed by applying a cause assumption rule. As the cause assumption rule, an abnormal stand is assumed from an actual louver angle, an actual speed correction value for a stand mill, an actual torque and an actual rolling load of a mill motor etc. For example, a speed set value of a mill stand is corrected from the actual louver angle or a forwarding rate set value is



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corrected from the speed correction value.

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## LEGAL STATUS

[Date of request for examination] 24.07.2001

[Date of sending the examiner's decision of rejection]

[Kind of final disposal of application other than the examiner's decision of rejection or application converted registration]

[Date of final disposal for application]

[Patent number] 3333452

[Date of registration] 26.07.2002

[Number of appeal against examiner's decision of rejection]

[Date of requesting appeal against examiner's decision of rejection]

[Date of extinction of right]

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